

# Can we claim charge multiplication in heavily irradiated segmented detectors?

<u>G. Casse</u>, A. Affolder, H. Brown, I. McLeod, M. Wormald

G. Casse, 14th RD50, Freiburg 5-7 June 2009.

## OUTLINE

- Comparison of thin and thick sensors after proton irradiation
- Studies at low temperature (-50°C)
- Non-linearity of  ${\rm N}_{\rm eff}\,{\rm vs}\,\Phi$
- Conclusions

## Irradiations:

24GeV/c protons Irrad1 CERN/PS: shuttle at Room Temperature (~30°C) and cold (<5°C) irradiations. Many thanks to M. Glaser.

26MeV p, Karlsruhe Cyclotron, cold. Many thanks to A. Dierlamm and W. De Boer

## Samples:

140 and 300 $\mu$ m thick miniature strip sensors, 1x1 cm<sup>2</sup> produced by Micron on RD50 4" mask.

### MEASUREMENTS: at -25 and -45/50 °C.

Rather nice and efficient method to have almost stable temperature using liquid N for cooling





#### 300 mm n-in-p Micron sensors

RED: irradiated with 24GeV/c protons Other: 26MeV protons 24GeV/c protons irradiated COLD, all but the 3.1E15 cm<sup>-2</sup> series



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# 140 and 300 $\mu$ m n-in-p Micron sensors after 1.9 and 3.1x10<sup>15</sup> n<sub>eq</sub> 24GeV/c p



# 140 and 300 $\mu$ m n-in-p Micron sensors after 5.6 and 1x10<sup>16</sup> n<sub>eq</sub> 24GeV/c p

#### Cold(0-5 °C) irradiation



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### 140 and 300 $\mu m$ n-in-p Micron sensors after 1x10^{16} $n_{eq}$ 26MeV p



# 140 and 300 $\mu$ m n-in-p Micron sensors after 5x10<sup>15</sup> n<sub>eq</sub> 26MeV p

### Cold irradiation, <u>evidence of charge multiplication</u> <u>effect: not only charge is recovered, but increased</u> bv f = 1.75



#### 140 and 300 µm n-in-p Micron sensors after 5 (26MeV p) and 10x10<sup>15</sup> n<sub>eq</sub> (24GeV/c p) at low (-50°C) T.



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0

Bias (V)

1400

#### **Special effects: forward bias**



Comment: this multiplication concept takes time to sink-in, but it has been a while since the CCE results puzzled us for being much better than expected from the anticipation of trapping. Just remind another direct result of this, from I. Mandic at the 12<sup>th</sup> RD50 workshop.



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#### CCE and currents after neutron irradiations



# Reverse currents of 140 and 300 µm n-in-p Micron sensors after various proton doses



 $N_{eff}$  vs  $\phi$  measured with the CV characteristic of 300  $\mu m$  n-in-p Micron sensors after 80 min 60°C annealing time

 $\beta$  = 0.028 ± 0.002 cm<sup>-1</sup>

# $N_{eff}$ vs $\phi$ measured with the CV characteristic of 140 $\mu m$ n-in-p Micron sensors after 80 min 60°C annealing time

 $\beta$  calculated for dose up to 5x10<sup>14</sup> n<sub>eq</sub> cm<sup>-2</sup>  $\beta$  = 0.023 ± 0.002 cm<sup>-1</sup>  $\beta$  calculated for dose up to 5x10<sup>14</sup> n<sub>eq</sub> cm<sup>-2</sup>  $\beta$  = 0.0022 ± 0.0003 cm<sup>-1</sup>

Seen also by Ljubljana (G. Kramberger et al., 12<sup>th</sup> RD50 workshop)

### CONCLUSIONS

Can we claim charge multiplication in heavily irradiated segmented detectors?

### YES, WE CAN!

But for the time being we proved it with Micron detectors only. This could well not be a coincidence, related to the junction formation and depth profile.

But also other effects are contributing to enhancing the collected charge after heavy irradiations: field dependant charge detrapping(?), lower than expected (non-linear behaviour, saturation?) so-called full depletion. This is nice, more investigations to do!

## Spare slides

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 $\alpha$  (300µm thick) = 3.2x10<sup>-17</sup> A cm<sup>-2</sup>.  $\alpha$  (140µm thick) = 2.7x10<sup>-17</sup> A cm<sup>-2</sup>.